Notice of References Cited	Application/Control No. 10/585,655	Applicant(s)/Patent Under Reexamination TAKUMAI ET AL.		
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 06225379 A	08-1994	Japan	FURUTA et al.	H04R 1/40
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	Р					
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	R					
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NON-PATENT DOCUMENTS

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